

09980509\_CLS  
Most Frequently Occurring Classifications of Patents Returned  
From A Search of 09980509 on July 11, 2003

Original Classifications

9 365/201  
5 324/765  
5 714/718  
4 714/724  
4 714/726  
3 714/736  
3 714/738  
2 324/158.1  
2 331/57  
2 714/731  
2 716/6

Cross-Reference Classifications

8 365/233  
8 714/724  
7 365/201  
5 324/158.1  
4 714/736  
4 714/742  
3 714/718  
3 714/738  
3 714/744  
2 324/617  
2 324/633  
2 324/73.1  
2 324/765  
2 327/265  
2 365/194  
2 365/203  
2 365/230.08  
2 368/118  
2 368/120  
2 714/30  
2 714/39  
2 714/725  
2 714/741  
2 714/815  
2 716/4

Combined Classifications

16 365/201  
12 714/724  
8 365/233

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8 714/718  
7 324/158.1  
7 324/765  
7 714/736  
6 714/738  
4 714/726  
4 714/742  
3 714/731  
3 714/744  
2 324/617  
2 324/633  
2 324/73.1  
2 327/265  
2 331/57  
2 365/189.05  
2 365/194  
2 365/203  
2 365/230.08  
2 368/118  
2 368/120  
2 714/30  
2 714/39  
2 714/723  
2 714/725  
2 714/741  
2 714/743  
2 714/815  
2 716/4  
2 716/6

## 09980509\_CLSTITLES

## Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09980509 on July 11, 2003

16 365/201 (9 OR, 7 XR)  
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
365/189.01 READ/WRITE CIRCUIT  
365/201 .Testing

12 714/724 (4 OR, 8 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing

8 365/233 (0 OR, 8 XR)  
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
365/230.01 ADDRESSING  
365/233 .Sync/clocking

8 714/718 (5 OR, 3 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/718 .Memory testing

7 324/158.1 (2 OR, 5 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/158.1 MISCELLANEOUS

7 324/765 (5 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .Of individual circuit component or element  
324/765 ..Test of semiconductor device

7 714/736 (3 OR, 4 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/736 ..Device response compared to expected  
fault-free response

6 714/738 (3 OR, 3 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT

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DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/738 ..Including test pattern generator

4 714/726 (4 OR, 0 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive scan  
design (LSSD))

4 714/742 (0 OR, 4 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/738 ..Including test pattern generator  
714/742 ...Testing specific device

3 714/731 (2 OR, 1 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive scan  
design (LSSD))  
714/731 ...Clock or synchronization

3 714/744 (0 OR, 3 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/738 ..Including test pattern generator  
714/744 ...Clock or synchronization

2 324/617 (0 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES  
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE  
RELATIONSHIPS  
324/612 .Parameter related to the reproduction or  
fidelity of a signal affected by a circuit

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t under test

324/615 ..Transfer function type characteristics  
324/617 ...Response time or phase delay

2 324/633 (0 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES  
REPRESENTATIVE OF ELECTRICAL STIMULUS/RES

PONSE

## RELATIONSHIPS

324/629 .Distributive type parameters  
324/633 ..Using resonant frequency

2 324/73.1 (0 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

2 327/265 (0 OR, 2 XR)

Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR  
DEVICES, CIRCUITS, AND SYSTEMS  
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING  
327/261 .Having specific delay in producing output  
waveform  
327/263 ..Delay interval set by rising or falling edge  
327/264 ...Having specific active circuit element or  
structure (e.g., FET, complementary transi  
stors, etc.)  
327/265 ....With counter

2 331/57 (2 OR, 0 XR)

Class 331 : OSCILLATORS  
331/57 RING OSCILLATORS

2 365/189.05 (1 OR, 1 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
365/189.01 READ/WRITE CIRCUIT  
365/189.05 .Having particular data buffer or latch

2 365/194 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
365/189.01 READ/WRITE CIRCUIT  
365/191 .Signals  
365/194 ..Delay

2 365/203 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
365/189.01 READ/WRITE CIRCUIT

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365/203

.Precharge

2 365/230.08 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL

365/230.01 ADDRESSING

365/230.08 .Including particular address buffer or latch  
circuit arrangement

2 368/118 (0 OR, 2 XR)

Class 368 : HOROLOGY: TIME MEASURING SYSTEMS OR DEVICES

368/89 TIME INTERVAL

368/107 .Electrical or electromechanical

368/113 ..Stop time type

368/118 ...Including time base oscillator

2 368/120 (0 OR, 2 XR)

Class 368 : HOROLOGY: TIME MEASURING SYSTEMS OR DEVICES

368/89 TIME INTERVAL

368/107 .Electrical or electromechanical

368/113 ..Stop time type

368/120 ...Including delay means

2 714/30 (0 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/25 ..Fault locating (i.e., diagnosis or testing)

714/27 ...Particular access structure

714/30 ....Built-in hardware for diagnosing or testin

g

or test mode  
within-system component (e.g., microprocess  
circuit, scan path)

2 714/39 (0 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/25 ..Fault locating (i.e., diagnosis or testing)

714/37 ...Analysis (e.g., of output, state, or design

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714/39      ....Monitor recognizes sequence of events
              (e.g., protocol or logic state analyzer)

2  714/723      (1 OR, 1 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/718      .Memory testing
714/723      ..Error mapping or logging

2  714/725      (0 OR, 2 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/724      .Digital logic testing
714/725      ..Programmable logic array (PLA) testing

2  714/741      (0 OR, 2 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/724      .Digital logic testing
714/738      ..Including test pattern generator
714/741      ...Simulation

2  714/743      (1 OR, 1 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/724      .Digital logic testing
714/738      ..Including test pattern generator
714/743      ...Addressing

2  714/815      (0 OR, 2 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/799      .Error/fault detection technique
714/811      ..Forbidden combination or improper condition

714/815      ...Time delay/interval monitored

2  716/4        (0 OR, 2 XR)
      Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
                  CIRCUIT OR SEMICONDUCTOR MASK
716/1        CIRCUIT DESIGN

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	716/4	.Testing or evaluating
2	716/6	(2 OR, 0 XR)
	Class	716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
		CIRCUIT OR SEMICONDUCTOR MASK
	716/1	CIRCUIT DESIGN
	716/4	.Testing or evaluating
	716/5	..Design verification (e.g., wiring line
		capacitance, fan-out checking, minimum pat
h width)		
	716/6	...Timing analysis (e.g., delay time, path
		delay, latch timing)



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6317372 91  
6175939 78  
6553529 78  
4775977 75  
5499248 71  
5794175 71  
5606567 71  
4893072 71  
6144262 71  
6195772 71  
6232845 71  
4631724 71  
6049901 71  
6119257 71  
6223314 71  
6223314 71  
4477902 71  
4608669 71  
5177440 71  
5195097 71  
5268639 71  
5325053 71  
5351211 71  
5357195 71  
5432797 71  
5734660 71  
5757705 71  
5872797 71  
5969653 71  
5995426 71  
5996098 71  
6097206 71  
6104651 71  
6114870 71  
6157200 71  
6158029 71  
6201746 71  
6226765 71  
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6253360 71  
6255843 71  
6275057 71  
6275428 71  
6298465 71  
6360343 71  
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6377065 71  
6400625 71

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6404218 71  
6404684 71